

A new way of understanding the role of each measurement at future Higgs factories in SMEFT

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Starting from precision measurements at an $e+e-$ Higgs factory, it is possible to extract the Higgs boson couplings using a general fit to the parameters of Standard Model Effective Field Theory (SMEFT). To understand the precisions that are possible, and to evaluate the role of each measurement offered by various Higgs factory proposals, it is important to understand the dependence of each output couplings on the accuracies of a large number of input measurements. In this talk, we present those dependencies in a new and transparent way and discuss their physics implications.

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